


<b>Search Notes</b>  	<b>Application/Control No.</b>  10607020	<b>Applicant(s)/Patent Under Reexamination</b>  HILL ET AL.
	<b>Examiner</b>  Le Nguyen	<b>Art Unit</b>  2174

SEARCHED			
Class	Subclass	Date	Examiner
715	752, 963	11/13/07	lvn
715	752, 963	2/25/2009	lvn

SEARCH NOTES		
Search Notes	Date	Examiner
confirmed allowance w/Sy Luu	6/21/07	lvn
US-PGPub, USPAT: 715/751-753; 709/204-207	11/13/07	lvn
EPO, JPO	11/13/07	lvn
ACM library, IEEE Xplore	11/13/07	lvn
confirmed allowance w/Raymond Bayerl	6/25/07	lvn
confirmed allowance w/Steve Sax	11/26/07	lvn
updated search	2/25/2009	lvn

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
715	752, 963	11/13/07	lvn
715	752, 963	2/25/2009	lvn

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